



JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO., LTD

TO-252-2LK Plastic-Encapsulate Thyristors

CT306D 3Q TRIACs

MAIN CHARACTERISTICS

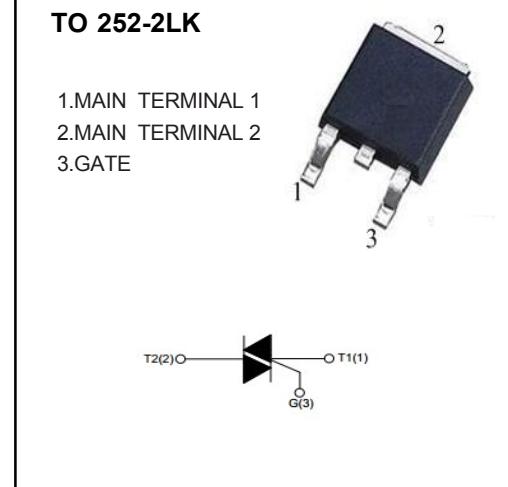
$I_{T(RMS)}$		6A
V_{DRM}/V_{RRM}	CT306D-600S/C	600V
	CT306D-800S/C	800V
V_{TM}		1.55V

FEATURES

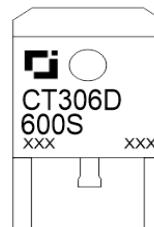
- NPNPN 5-layer Structure TRIACs
- Mesa Glass Passivated Technology
- Multi Layers Metal Electrodes
- High Junction Temperature
- Good Commutation Performance
- High dV/dt and dl/dt

APPLICATIONS

- Heater Control
- Motor Speed Controller
- Mixer



MARKING

CT306D:Series Code
600S:Depends on V_{DRM} and I_{GT}

XXX:Internal Code

ABSOLUTE RATINGS ($T_a=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Test condition		Value	Unit
V_{DRM}/ V_{RRM}	Repetitive peak off-state voltage	$T_j=25^\circ C$	CT306D-600S/C	600	V
			CT306D-800S/C	800	V
$I_{T(RMS)}$	RMS on-state current	TO-252-2LK($T_C \leq 110^\circ C$), Fig. 1,2		6	A
I_{TSM}	Non repetitive surge peak on-state current	Full sine wave , $T_j(\text{init})=25^\circ C$, $t_p=20\text{ms}$; Fig. 3,5		60	A
I^2t	I^2t value	$t_p=10\text{ms}$		18	A^2s
dI_T/dt	Critical rate of rise of on-state current	$I_G=2*I_{GT}$, $t_r \leq 10\text{ns}$, $F=120\text{Hz}$, $T_j=125^\circ C$	I - II - III	50	$\text{A}/\mu\text{s}$
			IV	n/a	
I_{GM}	Peak gate current	$t_p=20\mu\text{s}$, $T_j=125^\circ C$		2	A
$P_{G(AV)}$	Average gate power	$T_j=125^\circ C$		0.5	W
T_{STG}	Storage temperature			-40~+150	$^\circ C$
T_j	Operating junction temperature			-40~+125	

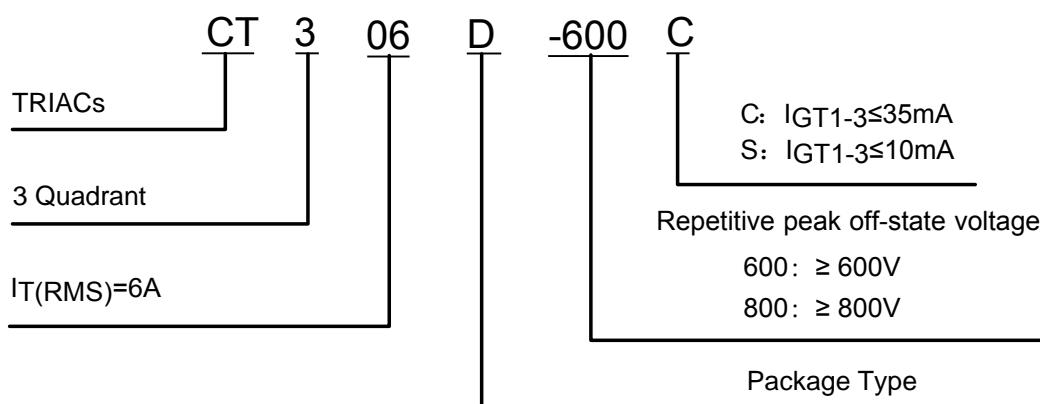
ELECTRICAL CHARACTERISTICS ($T_a=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test condition	Value		Unit
			S	C	
I_{GT}	Gate trigger current	$V_D=12\text{V}$, $I_T=0.1\text{A}$, $T_j=25^\circ\text{C}$, Fig. 6	≤ 10	≤ 35	mA
			n/a	n/a	
V_{GT}	Gate trigger voltage	$I - \text{II} - \text{III}$	≤ 1.3		V
V_{GD}	Non-triggering gate voltage	$V_D=V_{DRM}$, $T_j=125^\circ\text{C}$	≥ 0.2		V
I_H	Holding current	$V_D=12\text{V}$, $I_{GT}=0.1\text{A}$, $T_j=25^\circ\text{C}$, Fig. 6	≤ 15	≤ 25	mA
I_L	Latching current		≤ 20	≤ 30	mA
			≤ 25	≤ 35	mA
dV_D/dt	Critical rate of rise of off-state	$V_D=67\%V_{DRM}$, Gate Open $T_j=125^\circ\text{C}$	≥ 40	≥ 80	V/ μs
V_{TM}	On-state Voltage	$I_{TM}=8.5\text{A}$, $t_p=380\ \mu\text{s}$, Fig. 4	≤ 1.55		V
I_{DRM} / I_{RRM}	Repetitive peak off-state current	$V_D=V_{DRM}/V_{RRM}$, $T_j=25^\circ\text{C}$	≤ 5	≤ 5	μA
		$V_D=V_{DRM}/V_{RRM}$, $T_j=125^\circ\text{C}$	≤ 1	≤ 1	mA

THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
$R_{th} (j-c)$	Junction to case (AC)	2.1	$^\circ\text{C/W}$
$R_{th} (j-a)$	Junction to ambient	70	$^\circ\text{C/W}$

PART NUMBER



CHARACTERISTICS CURVES

FIG.1: Maximum power dissipation versus RMS on-state current (full cycle)

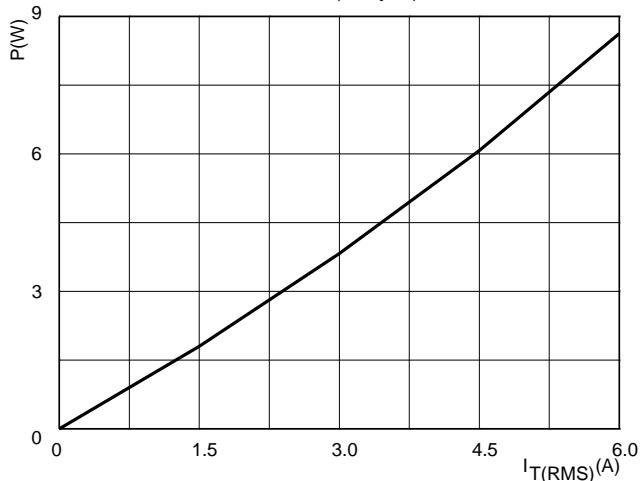


FIG.2: RMS on-state current versus case temperature (full cycle)

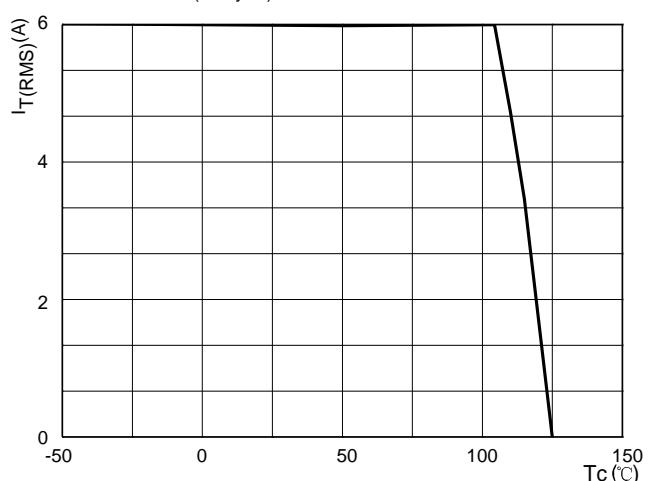


FIG.3: Surge peak on-state current versus number of cycles

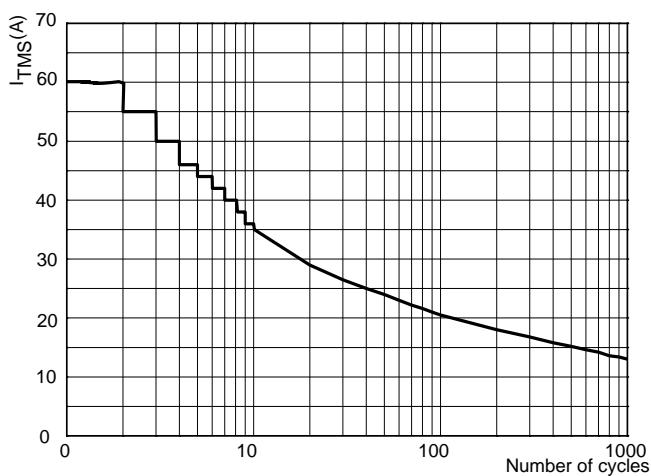


FIG.4: On-state characteristics (maximum values)

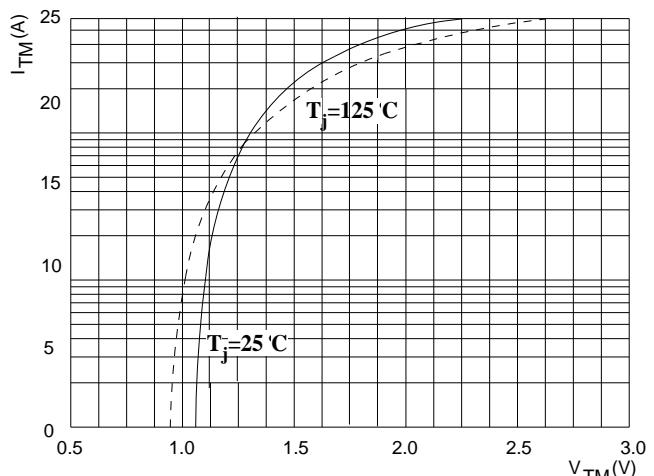


FIG.5: Non-repetitive surge peak on-state current for a sinusoidal pulse with width $t_p < 10\text{ms}$

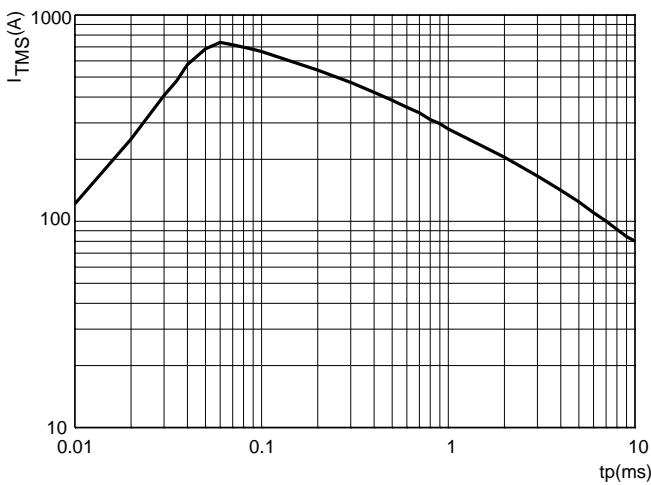
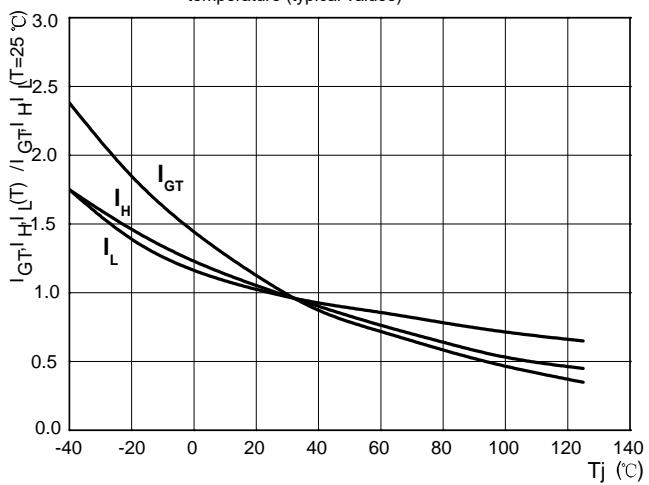
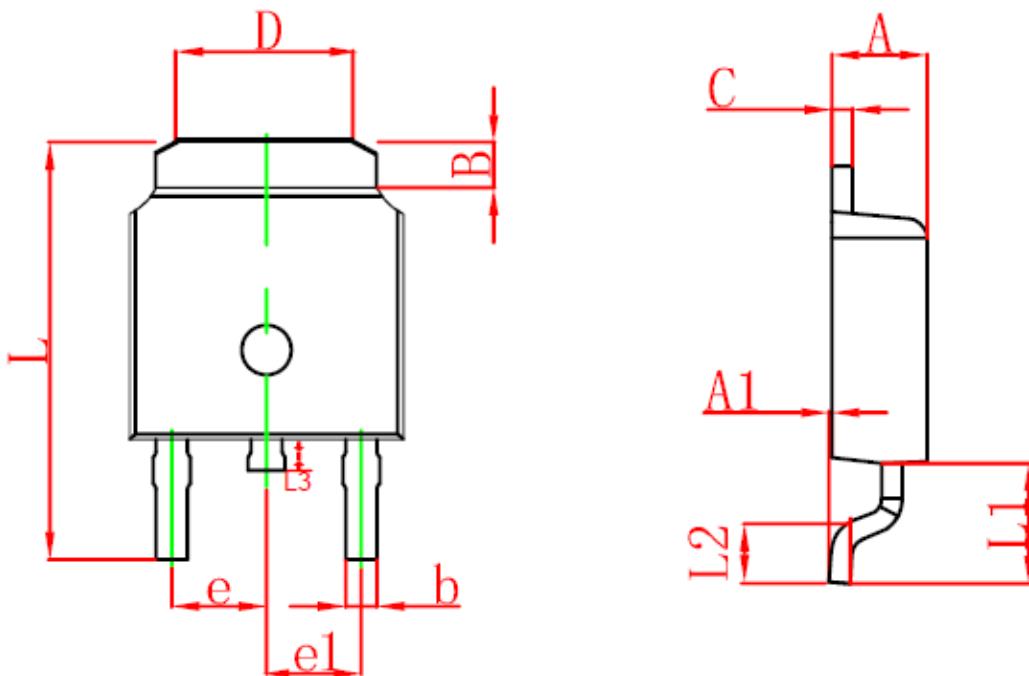


FIG.6: Relative variations of gate trigger current, holding current and latching current versus junction temperature (typical values)



TO-252-2LK PACKAGE OUTLINE DIMENSIONS



Symbol	Dimensions In Millimeters	
	Min.	Max.
A	2.100	2.500
A1	0.000	0.127
B	1.070	1.470
b	0.710	0.810
C	0.700	0.900
D	3.400	3.800
e	2.250	2.350
el	2.250	2.350
L	10.000	10.400
L1	2.600	3.000
L2	1.400	1.700
L3	0.600	1.000